

Thin Film Analysis by X-Ray Scattering

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Table of Contents

Preface IX

Symbols XV

1	Principles of X-ray Diffraction 1
1.1	The Basic Phenomenon 1
1.2	The $\theta/2\theta$ Scan 11
1.3	Intensity of Bragg Reflections 14
1.3.1	Atomic Form Factors 17
1.3.2	Structure Factor 19
1.3.3	Multiplicity 24
1.3.4	Geometry Factor 25
1.3.5	Preferred Orientation (Texture) 25
1.3.6	Polarization Factor 26
1.3.7	Absorption Factor 26
1.3.8	Integration of the Interference Function 29
1.4	Applications 37
	Exercises 39
	References 41
2	Identification of Chemical Phases 43
2.1	Histogram-Based Techniques 43
2.2	Linear Attenuation Coefficient μ 55
2.3	Determination and Interpretation of the μt Product 60
2.4	Analysis of Phase Mixtures 66
2.5	Amorphous Thin Films 70
2.6	Accurate Determination of Lattice Parameter 74
2.7	Applications 80
	Exercises 81
	References 83

3	Line Profile Analysis 85
3.1	Model Functions and Peak Parameters 86
3.2	Instrumental Line Profile 97
3.3	Deconvolution by Fourier Techniques 101
3.4	Reflection Broadening by Small Crystallite Size Only 107
3.4.1	Scherrer Equation 108
3.4.2	Column Height Distribution 111
3.4.3	Crystallite Shapes Other Than Cubes 112
3.4.4	Determination of the Column Height Distribution Function 115
3.4.5	Determination of the Crystallite Size Distribution Function 118
3.5	Concomitant Occurrence of Size and Strain Broadening 120
3.5.1	Analysis According to Williamson and Hall 122
3.5.2	Method of Warren and Averbach 126
3.5.3	Single-Line Analysis 129
3.5.4	Techniques of Whole-Pattern Fitting 130
3.6	Applications 134
	Exercises 136
	References 138
4	Grazing Incidence Configurations 143
4.1	Grazing Incidence X-ray Diffraction (GIXRD) 148
4.2	Penetration Depth and Information Depth 155
4.3	Depth-Dependent Properties 158
4.4	Refractive Index for X-rays 160
4.5	Total External Reflection and Critical Angle 161
4.6	X-ray Reflectivity (XRR) 165
4.6.1	Reflectivity of a Substrate 166
4.6.2	Reflectivity of a Single Layer 168
4.6.3	Reflectivity of Multilayers and Superlattices 171
4.7	Grazing Incidence Diffraction (GID) 175
4.8	Applications 177
	Exercises 179
	References 181
5	Texture and Preferred Orientation 183
5.1	Texture Factors 188
5.2	Pole Figures 191
5.3	Measurement of Pole Figures 195
5.4	Directions, Orientations and Inverse Pole Figures 200
5.5	Fiber Textures or Layer Textures 204
5.5.1	Harmonic Method 204
5.5.2	Whole Pattern Techniques 207
5.5.3	Rocking Curves (ω Scans) 211
5.6	Biaxial and Fully General Textures 216
5.6.1	Azimuthal Scans (ϕ Scans) 218
5.6.2	General Orientation Distribution 220

5.6.3	Determination of Fully General Texture	225
5.7	Depth Dependence of Thin-Film Textures	228
5.8	Applications	230
	Exercises	234
	References	235
6	Residual Stress Analysis	239
	<i>Mario Birkholz and Christoph Genzel</i>	
6.1	Ceiiinosssttuv	241
6.2	Fundamental Equation of XSA	246
6.3	Measurement of d_{ψ} Distributions	249
6.4	Diffraction Elastic Constants (DECs) s_1 and $1/2s_2$	258
6.5	Grain Interaction Models	261
6.6	The Effect of Texture	265
6.7	Classification of Stresses	268
6.7.1	Classification by Dimension	268
6.7.2	Residual Stresses in Multiphase Materials	269
6.7.3	Origin of Residual Stresses: Extrinsic and Intrinsic Stresses	271
6.8	Effect of Residual Stress Gradients	273
6.8.1	General Considerations	273
6.8.2	The Biaxial Stress State	274
6.9	Detection of Residual Stress Gradients in Thin Films	276
6.9.1	Basic Relations	276
6.9.2	X-ray Penetration Depth for the General Case of Asymmetric Diffraction	278
6.9.3	Special Methods for X-ray Stress Gradient Analysis	281
6.9.4	Grazing-Incidence Diffraction (GID)	282
6.9.5	The Scattering Vector Method	284
6.9.6	Realization of H Mode on a Four-Circle Diffractometer	286
6.10	Applications	289
	Exercises	291
	References	291
7	High-Resolution X-ray Diffraction	297
	<i>Mario Birkholz and Paul F. Fewster</i>	
7.1	Strain, Strain Relaxation and Composition in Epitaxial Layers	303
7.2	High-Resolution Rocking Curves	306
7.3	Mosaicity and Extinction	314
7.4	Dynamical Theory of Ewald and Extensions	319
7.5	High-Resolution Rocking Curves and Profiles from Layer Structures	324
7.6	Reciprocal Space Mapping	332
7.7	Diffuse Scattering	337
7.8	Extensions to High-Resolution Diffraction	338
	Exercises	339
	References	340